

### 12500 TI Boulevard, MS 8640, Dallas, Texas 75243

## PCN#20160720001A Qualify ASESH as an additional Assembly & Test site for select devices Change Notification / Sample Request

**Date:** 8/2/2016

To: PREMIER FARNELL PCN

#### Dear Customer:

The purpose of this version A is to retract devices from this change notification. The retraction is for select devices that were inadvertently included and are not affected by this change. We apologize for any inconvenience this may have caused.

This is an announcement of a change to a device that is currently offered by Texas Instruments. The details of this change are on the following pages.

We request you acknowledge receipt of this notification within **30** days of the date of this notice. Lack of acknowledgement of this notice within 30 days constitutes acceptance of the change. If you require samples or additional data to support your evaluation, please request within 30 days.

The proposed first ship date is indicated on page 3 of this notification, unless customer agreement has been reached on an earlier implementation of the change.

This notice does not change the end-of-life status of any product. Should product affected be on a previously issued product withdrawal/discontinuance notice, this notification does not extend the life of that product or change the life time buy offering/discontinuance plan.

For questions regarding this notice, contact your local Field Sales Representative or the PCN Manager (PCN www admin team@list.ti.com).

Sincerely,

PCN Team SC Business Services

## 20160720001A Change Notification / Sample Request Attachments

## **Products Affected:**

The devices listed on this page are a subset of the complete list of affected devices. According to our records, these are the devices that you have purchased within the past twenty-four (24) months. The corresponding customer part number is also listed, if available.

DEVICE	<b>CUSTOMER PART NUMBER</b>
MAX3221CPW	null
MAX3221CPWE4	null
MAX3221IPW	null
MAX3221IPWG4	null
MAX3221IPWR	null
TRS3221EIPW	null
MAX3221EIPW	null
MAX3221EIPWR	null
MAX3221ECPW	null

Technical details of this Product Change follow on the next page(s).

PCN Number: 20160720001A PCN Date: 08/02/20												
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							on production release the revised reports can be					
					obtained t	from the	TI ECO web	site	<u>2</u> .			

## Changes to product identification resulting from this PCN:

Assembly Site		
TI Malaysia	Assembly Site Origin (22L)	ASO: MLA
ASESH	Assembly Site Origin (22L)	ASO: ASH

Sample product shipping label (not actual product label)



(1P) \$N74L\$07N\$R (Q) 2000 (D) 0336 (31T)LOT: 3959047MLA (4W) TKY(1T) 7523483\$12 (P) (V) 0033317

(2P) REV: (V) 0033317 (20L) CSO: SHE (21L) CCO:USA (22L) ASO: MLA (23L) ACO: MYS

## Topside Device marking:

TTEM: 5A (L)TO:3750

Assembly site code for MLA = K

Assembly site code for ASH = A

#### **Product Affected**

MAX3221CPW	MAX3221ECPWG4	MAX3221IPW	TRS3221ECPWR-LI
MAX3221CPWE4	MAX3221ECPWR	MAX3221IPWG4	TRS3221EIPW
MAX3221CPWG4	MAX3221EIPW	MAX3221IPWR	TRS3221EIPWR
MAX3221CPWR	MAX3221EIPWE4	MAX3221IPWRG4	TRS3221EIPWRG4
MAX3221CPWRE4	MAX3221EIPWG4	TRS3221CPWR	TRS3221IPW
MAX3221CPWRG4	MAX3221EIPWR	TRS3221CPWRG4	TRS3221IPWR
MAX3221ECPW	MAX3221EIPWRE4	TRS3221ECPW	
MAX3221ECPWE4	MAX3221EIPWRG4	TRS3221ECPWR	

# Qualification Report Multisource MAX3221ECPWR and MAX3221CPWR to ASESH Approve Date 01-Jul-2016

## **Product Attributes**

Attributes	Qual Device: MAX3221CPWR	Qual Device: MAX3221ECPWR	QBS Product Reference: TRS3243CDB	QBS Process Reference: MAX232ECDW	QBS Process Reference: MAX3237EDW
Assembly Site	ASESH	ASESH	MLA	MLA	MLA
Package Family	TSSOP	TSSOP	SSOP	SOIC	SOIC
Flammability Rating	UL 94 V0	UL 94 V0	UL 94 V0	UL 94 V-0	UL 94 V-0
Wafer Fab Supplier	DFAB	DFAB	DFAB	DFAB	DFAB
Wafer Process	LBC3S	LBC3S	LBC3S	LBC3S	LBC3S

Attributes	QBS Process Reference: SN75C3238EDW	QBS Package Reference: SN74LV14APWR	QBS Package Reference: SN74LVC14APWR	QBS Package Reference: ULN2003APW
Assembly Site	TAI	ASESH	ASE-SH	ASESH
Package Family	SOIC	TSSOP	TSSOP	TSSOP
Flammability Rating	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0
Wafer Fab Supplier	DFAB	SFAB	FFAB	SFAB
Wafer Process	LBC3S	EPIC1-S	P9750	JI

<sup>-</sup> QBS: Qual By Similarity

## **Qualification Results**

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: MAX3221CPWR	Qual Device: MAX3221ECP WR	QBS Product Reference: TRS3243CDB	QBS Process Reference: MAX232ECD W
AC	Autoclave 121C	96 Hours	-	-	-	-
ED	Electrical Characterization	Per Datasheet Parameters	-	-	Pass	Pass
HAST	Biased HAST, 130C/85%RH	96 Hours	-	-	-	-
ESD	ESD - IEC Air Gap	15000 V	-	-	-	1/3/0
HBM	ESD - HBM	4000 V	1/3/0	1/3/0	-	-
HBM	ESD - HBM -HIGH	15000 V	-	-	1/3/0	1/3/0
CDM	ESD - CDM	1500 V	1/3/0	1/3/0	-	1/3/0
HTOL	Life Test, 150C	300 Hours	-	-	1/77/0	-
HTSL	High Temp. Storage Bake, 150C	1000 Hours	-	-	-	-
LU	Latch-up	(per JESD78)	1/6/0	1/6/0	1/6/0	3/9/0
TC	Temperature Cycle, -65C/150C	500 Cycles	-	-	-	-
ТНВ	Biased Temperature and Humidity, 85C/85%RH	1000 Hours	-	-	-	-
UHAST	Unbiased HAST 130C/85%RH	96 Hours	-	-	-	-
WBP	Bond Strength	Wires	-	-	-	-

Туре	Test Name / Condition	Duration	QBS Process Reference: MAX3237E DW	QBS Process Reference: SN75C3238 EDW	QBS Package Reference: SN74LV14 APWR	QBS Package Reference: SN74LVC14A PWR	QBS Package Reference: ULN2003AP W
AC	Autoclave 121C	96 Hours	1/77/0	1/77/0	-	-	-
ED	Electrical Characterization	Per Datasheet Parameters	-	-	Pass	Pass	Pass
HAST	Biased HAST, 130C/85%RH	96 Hours	-	-	1/77/0	1/77/0	1/77/0

<sup>-</sup> Qual Devices qualified at LEVEL1-260CG: MAX3221CPWR, MAX3221ECPWR

<sup>-</sup> Device MAX3221ECPWR contains multiple dies.

ESD	ESD - IEC Air Gap	15000 V	-	-	-	-	-
НВМ	ESD - HBM	4000 V	-	-	-	-	-
НВМ	ESD - HBM -HIGH	15000 V	-	-	-	-	-
CDM	ESD - CDM	1500 V	-	-	-	-	-
HTOL	Life Test, 150C	300 Hours	1/40/0	1/40/0	1/77/0	1/77/0	1/77/0
HTSL	High Temp. Storage Bake, 150C	1000 Hours	1/77/0	1/77/0	1/77/0	1/77/0	1/77/0
LU	Latch-up	(per JESD78)	-	-	-	-	-
TC	Temperature Cycle, - 65C/150C	500 Cycles	1/77/0	1/77/0	1/77/0	1/77/0	1/77/0
ТНВ	Biased Temperature and Humidity, 85C/85%RH	1000 Hours	1/26/0	1/26/0	-	-	-
UHAST	Unbiased HAST 130C/85%RH	96 Hours	-	-	1/77/0	1/77/0	1/77/0
WBP	Bond Strength	Wires	-	-	1/76/0	1/76/0	1/76/0

<sup>-</sup> Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

## Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com

<sup>-</sup> The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

<sup>-</sup> The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours

<sup>-</sup> The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles Quality and Environmental data is available at Tl's external Web site: http://www.ti.com/